



Deep Learning from Multi-Sourced Data

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Message from the Guest Editors

Dear Colleagues,

With the fast development of deep learning technologies, vast quantities of data are usually required for deep model training. It is worth employing complementary and rich information from multiple sourced datasets when a single dataset can not meet the demand. However, several challenges remain in the learning of multi-sourced data. Firstly, multi-sourced data can have different modalities. Combining information from multi-modality data is usually difficult. Secondly, label inconsistency is another major issue. Some data samples are annotated with fine labels, while some have weak labels or in some cases no labels. Thirdly, there are annotation biases among different annotators, resulting in noisy label problems. Fourthly, domain gaps usually exist in multi-sourced data. Despite these challenges, there is a high demand for practical applications related to multi-sourced data. As a result, learning from multi-sourced data is garnering more and more attention.

In this Special Issue, we welcome original research, applications, and review articles in all areas related to learning from multi-sourced data.





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Message from the Editor-in-Chief

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